

STGD6NC60H-1

N-channel 600 V, 7 A - IPAK Very fast PowerMESH™ IGBT

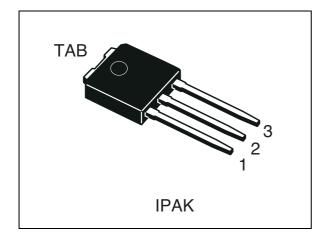
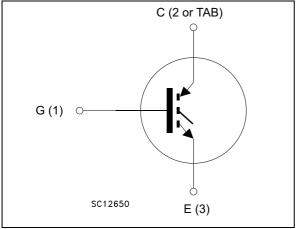


Figure 1. Internal schematic diagram



Datasheet - production data

Features

Туре	V _{CES}	V _{CE(sat)} max@25°C	I _С @100°С	
STGD6NC60H	600V	<2.5V	7A	

- Low on voltage drop (V_{cesat})
- Low C_{RES} / C_{IES} ratio (no cross-conduction susceptibility)
- High frequency operation

Description

Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESHTM IGBTs, with outstanding performances. The suffix H identifies a family optimized for high frequency application in order to achieve very high switching performances (reduced t_{fall}) maintaining a low voltage drop.

Applications

- High frequency inverters
- SMPS and PFC in both hard switch and resonant topologies
- Motor drivers

Table 1. Device summary

Part number	Marking	Package	Packaging
STGD6NC60H-1	GD6NC60H	IPAK	Tube

DocID025306 Rev 1

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1 Electrical ratings

Symbol	Parameter	Value	Unit
V _{CES}	Collector-emitter voltage (V _{GS} = 0)	600	V
I _C ⁽¹⁾	Collector current (continuous) at T _C = 25°C	15	А
I _C ⁽¹⁾	Collector current (continuous) at T _C = 100°C	7	А
I _{CM} ⁽²⁾	Collector current (pulsed)	21	А
V _{GE}	Gate-emitter voltage	±20	V
P _{TOT}	Total dissipation at $T_{C} = 25^{\circ}C$	62.5	W
T _{stg}	Storage temperature	– 55 to 150	°C
Тj	Operating junction temperature	- 33 10 130	
Τ _Ι	Maximum lead temperature for soldering purpose (for 10sec. 1.6 mm from case)	300	°C

Table 2.	Absolute	maximum	ratings
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1. Calculated according to the iterative formula:

$$I_{C}(T_{C}) = \frac{T_{JMAX}^{-T}C}{R_{THJ-C} \times V_{CESAT(MAX)}^{-T}(T_{C}, I_{C})}$$

2. Pulse width limited by max junction temperature

Table 3. Thermal resistance

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case max	2	°C/W
Rthj-amb	Thermal resistance junction-ambient max	100	°C/W



2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{BR(CES)}	Collector-emitter breakdown voltage	I _C = 1mA, V _{GE} = 0	600			V
V _{CE(sat)}	Collector-emitter saturation voltage	V _{GE} = 15V, I _C = 3A V _{GE} = 15V, I _C = 3A, Tc= 125°C		1.9 1.7	2.5	V V
V _{GE(th)}	Gate threshold voltage	V _{CE} = V _{GE} , I _C = 250 μA	3.75		5.75	V
I _{CES}	Collector cut-off current (V _{GE} = 0)	V _{CE} = 600V V _{CE} = 600V, T _C = 125°C			10 1	μA mA
I _{GES}	Gate-emitter leakage current (V _{CE} = 0)	V_{GE} = ±20V, V_{CE} = 0			±100	nA
9 _{fs}	Forward transconductance	V _{CE} = 15V _, I _C = 3A		3		S

Table 4. Static

Table 5. Dynamic

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Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{ies}	Input capacitance		-	205	-	pF
C _{oes}	Output capacitance	V _{CE} = 25V, f = 1MHz,	-	32	-	pF
C _{res}	Reverse transfer capacitance	V _{GE} = 0	-	5.5	-	pF
Qg	Total gate charge	V _{CE} = 390V, I _C = 3A,	-	13.6	-	nC
Q _{ge}	Gate-emitter charge	V _{GE} = 15V,		3.4		nC
Q _{gc}	Gate-collector charge	(see Figure 17)		5.1		nC
I _{CL}	Turn-off SOA minimum current	V _{clamp} =390V, Tj=150°C, R _G =10Ω, V _{GE} =15V	-	19	-	А



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V _{CC} = 390V, I _C = 3A	-	12	-	ns
t _r	Current rise time	R _G = 10Ω, V _{GE} = 15V,	-	5	-	ns
(di/dt) _{on}	Turn-on current slope	(see Figure 18)	-	612	-	A/µs
t _{d(on)}	Turn-on delay time	V _{CC} = 390V, I _C = 3A	-	13	-	ns
t _r	Current rise time	R _G = 10Ω, V _{GE} = 15V, Tj=125°C		4.3	-	ns
(di/dt) _{on}	Turn-on current slope	(see Figure 18)	-	560	-	Aµs
t _{r(Voff)}	Off voltage rise time	V _{CC} = 390V, I _C = 3A,	-	40	-	ns
t _{d(off)}	Turn-off delay time	R _{GE} = 10Ω, V _{GE} = 15V	-	76	-	ns
t _f	Current fall time	(see Figure 18)		100	-	ns
t _{r(Voff)}	Off voltage rise time	V _{CC} = 390V, I _C = 3A,	-	60	-	ns
t _{d(off)}	Turn-off delay time	R _{GE} = 10Ω, V _{GE} = 15V, Tj=125°C	-	98	-	ns
t _f	Current fall time	(see Figure 18)	-	124	-	ns

Table 6. Switching on/off (inductive load)

Table 7. Switching energy (inductive load)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
E _{on} ⁽¹⁾	Turn-on switching losses	V _{CC} = 390V, I _C = 3A	-	20	-	μJ
E _{off} ⁽²⁾	Turn-off switching losses	$R_G = 10\Omega, V_{GE} = 15V$	-	68	-	μJ
E _{ts}	Total switching losses	(see Figure 18)		88	-	μJ
E _{on} ⁽¹⁾	Turn-on switching losses $V_{CC} = 390V, I_C = 3A$		-	37	-	μJ
E _{off} ⁽²⁾	Turn-off switching losses	R _G = 10Ω, V _{GE} =15V, Tj= 125°C		93	-	μJ
E _{ts}	Total switching losses	(see Figure 18)	-	130	-	μJ

 Eon is the tun-on losses when a typical diode is used in the test circuit in *Figure 18*. If the IGBT is offered in a package with a co-pak diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature (25°C and 125°C)

2. Turn-off losses include also the tail of the collector current



Electrical characteristics (curves) 2.1

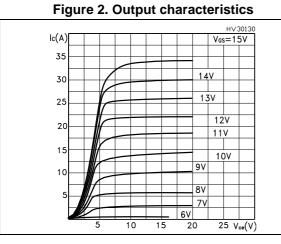
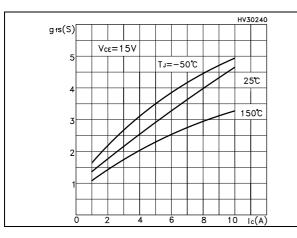
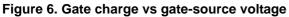


Figure 4. Transconductance





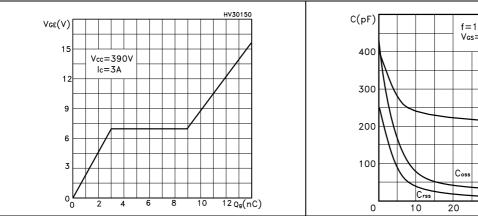


Figure 3. Transfer characteristics

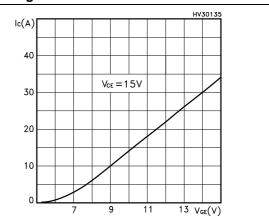


Figure 5. Collector-emitter on voltage vs temperature

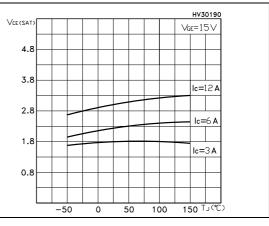


Figure 7. Capacitance variations

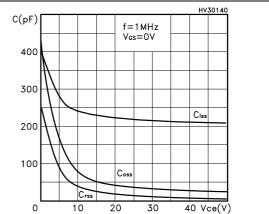




Figure 8. Normalized gate threshold voltage vs temperature

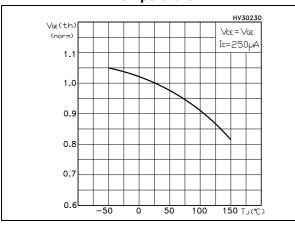


Figure 10. Normalized breakdown voltage vs temperature

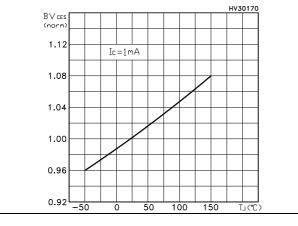


Figure 9. Collector-emitter on voltage vs collector current

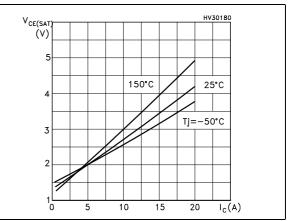


Figure 11. Switching losses vs temperature

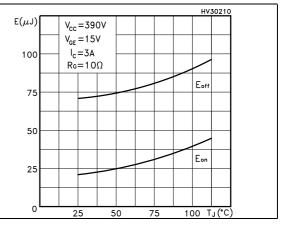


Figure 12. Switching losses vs gate resistance Figure 13. Switching losses vs collector current

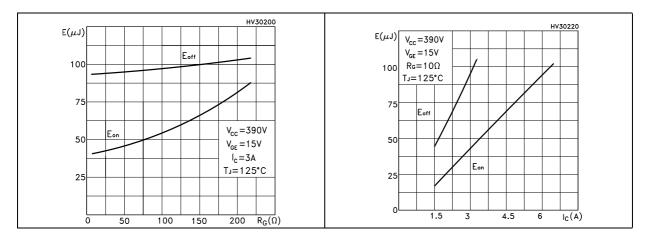
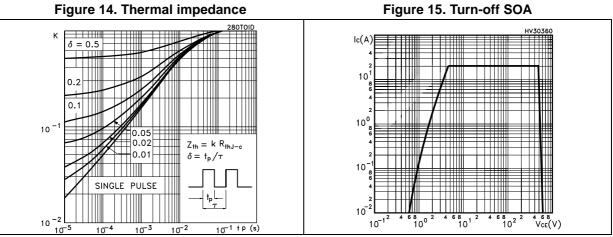




Figure 14. Thermal impedance





3 Test circuit

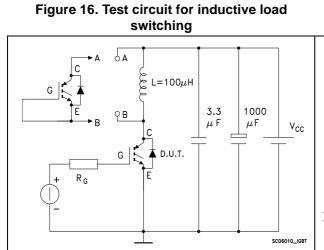
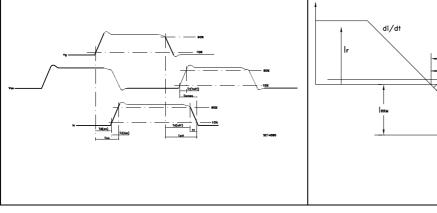
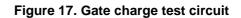
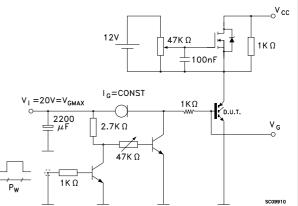
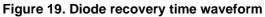


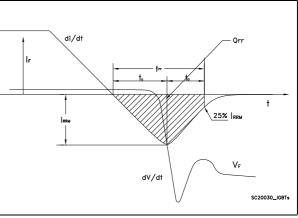
Figure 18. Switching waveform









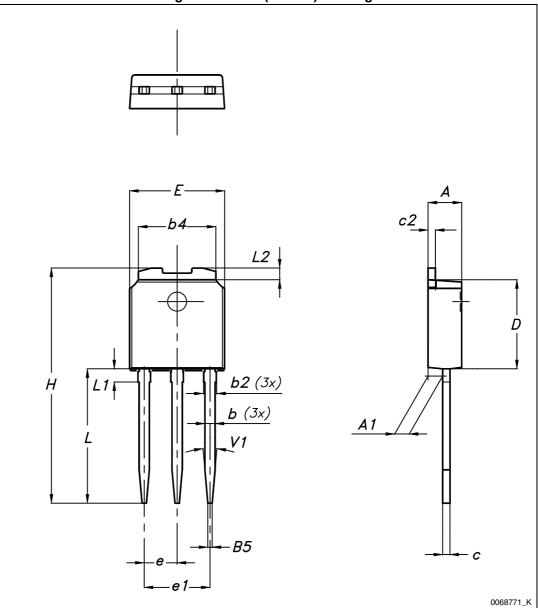




4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.

Figure 20. IPAK (TO-251) drawing





5.14		mm.	
DIM	min.	typ.	max.
А	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
С	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
E	6.40		6.60
е		2.28	
e1	4.40		4.60
Н		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	

Table 8. IPAK (TO-251) mechanical data



5 Revision history

Table 9. Revision history

Date	Revision	Changes
08-Apr-2014	1	First release.



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